

Notice of References Cited	Application/Control No. 10/816,164	Applicant(s)/Patent Under Reexamination TAKIZAWA ET AL.	
	Examiner David H. Chu	Art Unit 2672	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0157647	08-2004	Takahashi, Akira	455/566
*	B	US-2002/0158812	10-2002	Pallakoff, Matthew G.	345/5
*	C	US-2004/0239687	12-2004	Ideawa et al.	345/623
*	D	US-2003/0013417	01-2003	Bum, Jae Ryong	455/90
*	E	US-2005/0091431	04-2005	Olodort et al.	710/072
*	F	US-6,813,143	11-2004	Makela, Aarre	361/679
*	G	US-2003/0222853	12-2003	Kim, Joon-Young	345/169
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.